

UNISONIC TECHNOLOGIES CO., LTD

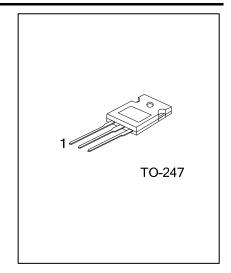
20N40 **Preliminary Power MOSFET**

400V, 23A N-CHANNEL POWER MOSFET

DESCRIPTION

The UTC 20N40 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

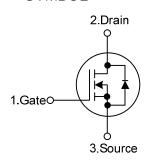
The UTC 20N40 is generally applied in high efficiency switch mode power supplies.



FEATURES

- * $R_{DS(ON)}$ =0.2 Ω @ V_{GS} =10V, I_{D} =11.5A
- * Low Gate Charge (Typical 46nC)
- * Low C_{RSS} (Typical 25pF)
- * High Switching Speed

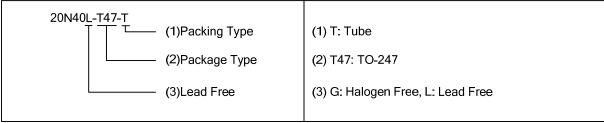
SYMBOL



ORDERING INFORMATION

Ordering Number		Deelsess	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
20N40L-T47-T	20N40G-T47-T	TO-247	G	D	S	Tube	

Pin Assignment: G: Gate D: Drain S: Source Note:



www.unisonic.com.tw 1 of 6

■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	400	٧
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous T _C =25°C	- I _D	23	Α
	T _C =100°C		13.8	Α
	Pulsed (Note 2)	I _{DM}	92	Α
Avalanche Current (Note 2)		I _{AR}	23	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	1190	mJ
	Repetitive (Note 2)	E _{AR}	23.5	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation (T _C =25°C)		ם	235	W
Derate above 25°C		P _D	1.8	W/°C
Junction Temperature		T_J	+150	°C
Storage Temperature		T _{STG}	-55~+150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 4.5mH, I_{AS} = 23A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 23A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	40	°C/W	
Junction to Case	$\theta_{ m JC}$	0.53	°C/W	

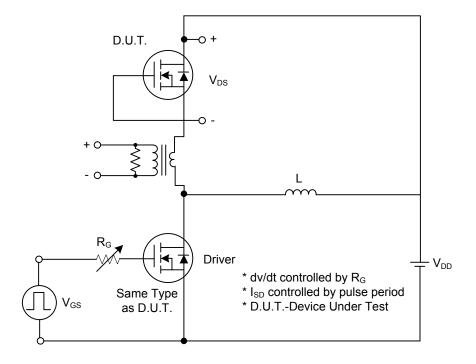
■ ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS				•			
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	400			V	
Breakdown Voltage Temperature Coefficient	$\triangle BV_{DSS}/\triangle T_{J}$	Reference to 25°C, I _D =250µA		0.5		V/°C	
Drain-Source Leakage Current	I _{DSS}	V _{DS} =400V, V _{GS} =0V			10	μΑ	
Gate- Source Leakage Current Forward		V_{GS} =+30V, V_{DS} =0V			+100	nA	
Reverse	I_{GSS}	V _{GS} =-30V, V _{DS} =0V			-100	nA	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.0		4.0	V	
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =11.5A		0.15	0.2	Ω	
DYNAMIC PARAMETERS							
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		2280	3030	pF	
Output Capacitance	Coss			370	490	pF	
Reverse Transfer Capacitance	C _{RSS}			25	38	pF	
SWITCHING PARAMETERS							
Total Gate Charge at 10V	$Q_{G(TOT)}$			46	60	nC	
Gate to Source Charge	Q_{GS}	V _{DS} =320V, I _D =23A (Note 1, 2)		13		nC	
Gate to Drain Charge	Q_{GD}			18		nC	
Turn-ON Delay Time	t _{D(ON)}			40	90	ns	
Rise Time	t _R	V_{DS} =200V, I_{D} =23A, R_{G} =25 Ω (Note 1, 2)		92	195	ns	
Turn-OFF Delay Time	t _{D(OFF)}			120	250	ns	
Fall-Time	t _F			75	160	ns	
SOURCE- DRAIN DIODE RATINGS AND C	HARACTERIST	TICS					
Maximum Body-Diode Continuous Current	Is				23	Α	
Maximum Body-Diode Pulsed Current	I _{SM}				92	Α	
Drain-Source Diode Forward Voltage	V _{SD}	I _{SD} =23A, V _{GS} =0V			1.5	V	
Body Diode Reverse Recovery Time	t _{rr}	I _{SD} =23A, V _{GS} =0V,		110		ns	
Body Diode Reverse Recovery Charge	Q_{RR}	dI _F /dt=100A/μs (Note 1)		0.3		μC	

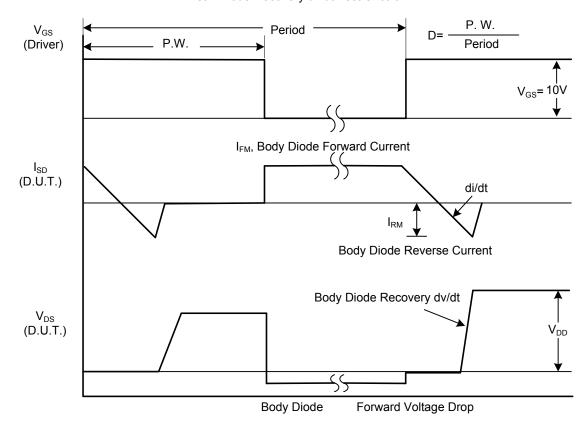
Notes: 1. Pulse Test: Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$

^{2.} Essentially Independent of Operating Temperature Typical Characteristics

TEST CIRCUITS AND WAVEFORMS

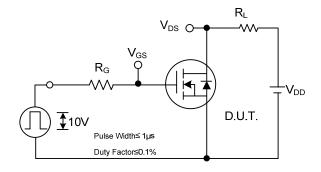


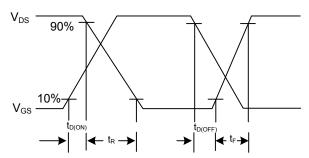
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

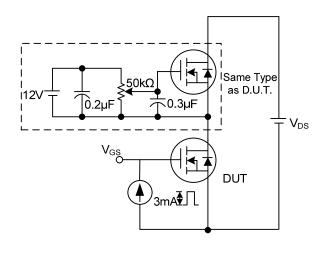
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

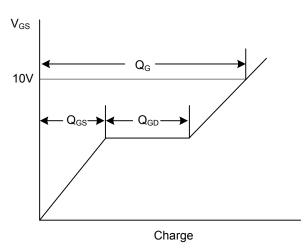




Switching Test Circuit

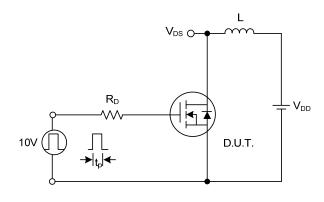
Switching Waveforms

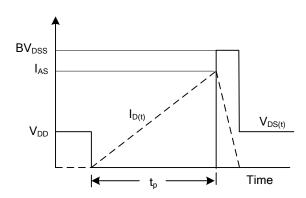




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. The information presented in this document does not form part of any quotation or contract, is believed to be accurate and reliable and may be changed without notice.

